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**Lithium tantalate and lithium niobate crystals for surface acoustic wave (SAW)
device applications - Specifications and measuring methods**

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CONTENTS

FOREWORD.....	3
1 Scope.....	5
2 Normative references	5
3 Terms and definitions	5
4 Requirements	7
4.1 Material specification	7
4.1.1 LN	7
4.1.2 LT.....	7
4.2 Requirements for as-grown crystal.....	7
4.2.1 Specifications	7
4.2.2 Macroscopic quality	8
4.2.3 Single domain	8
4.2.4 Curie temperature and tolerance	8
4.2.5 Lattice parameter	8
4.3 Requirements for lumbered crystal	8
4.3.1 As-grown crystal for lumbered crystal	8
4.3.2 Specifications	8
5 Sampling and inspection	9
5.1 General.....	9
5.2 Sampling and inspection plan	9
5.3 Determination of inspection results	10
6 Test methods.....	10
6.1 Test methods for as-grown crystal	10
6.1.1 Diameter and cylinder length	10
6.1.2 Macroscopic quality	10
6.1.3 Single domain	10
6.1.4 Curie temperature	10
6.1.5 Lattice parameter	10
6.2 Test methods for lumbered crystal	11
6.2.1 Surface orientation.....	11
6.2.2 Diameter.....	11
6.2.3 Orientation of orientation flat	11
6.2.4 Width of orientation flat	11
6.2.5 Effective length	11
6.2.6 Cylindricity	11
6.2.7 Verticality	11
7 Identification, labelling, packaging, delivery condition	11
7.1 Packaging	11
7.2 Labelling and identification	11
7.3 Terms of delivery	11
Annex A (normative) Measurement of single domain for LT and LN crystals	12
A.1 General.....	12
A.2 Measurement principle	12
A.3 Measurement	12
A.3.1 Scattered light path method.....	12
A.3.2 Etching method	13

A.3.3 Electromotive voltage method.....	15
Annex B (normative) Measurement of Curie temperature	17
B.1 General.....	17
B.2 DTA method.....	17
B.3 DSC method	18
B.4 Dielectric constant method	18
Annex C (normative) Measurement of lattice parameter (Bond method).....	20
Annex D (normative) Measurement of cylindricity for LT and LN crystals	22
D.1 General.....	22
D.2 Measurement	22
D.2.1 Equipment	22
D.2.2 Measuring procedure	22
D.2.3 Other instructions.....	23
Annex E (normative) Measurement of verticality for LT and LN crystals.....	24
E.1 General.....	24
E.2 Measurement	24
E.2.1 Equipment	24
E.2.2 Measuring procedure	24
Bibliography	25
Figure 1 – Schematic diagram of lumbered crystal.....	6
Figure 2 – Schematic diagram of verticality for lumbered crystal	7
Figure A.1 – Schematic diagram of sample position.....	14
Figure A.2 – Schematic diagram of measurement points.....	14
Figure A.3 – Examples of 42°Y-X LT after etching	14
Figure A.4 – Examples of 128°Y-X LN after etching	15
Figure A.5 – Schematic diagram of waveform for single-domain crystals	15
Figure A.6 – Schematic diagram of waveform for non-single-domain crystals	16
Figure B.1 – Schematic of a DTA system.....	17
Figure B.2 – Schematic of a DSC system	18
Figure B.3 – Schematic of a dielectric constant measurement system	19
Figure C.1 – The Bond method.....	21
Figure D.1 – Measurement schematic diagram of cylindricity	22
Figure E.1 – Measurement schematic diagram of verticality	24
Table 1 – Typical specifications of as-grown crystal.....	8
Table 2 – The centre value and tolerance of Curie temperature specification.....	8
Table 3 – Typical specifications of lumbered crystal.....	9
Table 4 – Sampling and inspection plan	10

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The text of this International Standard is based on the following documents:

Draft	Report on voting
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Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.